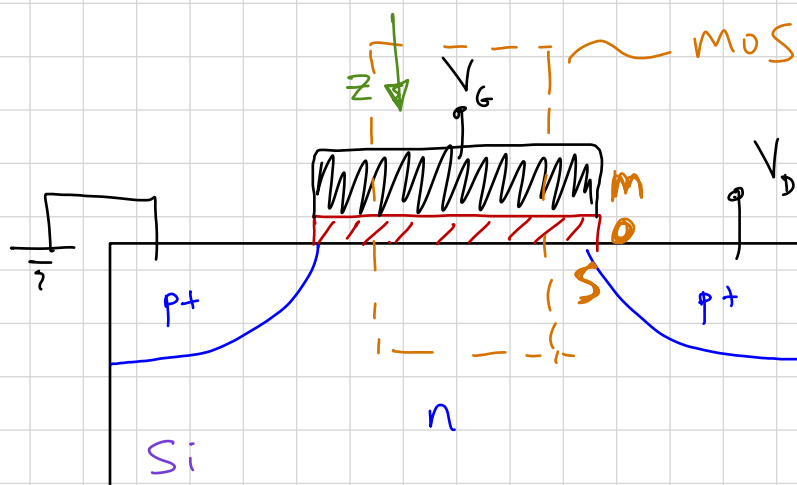
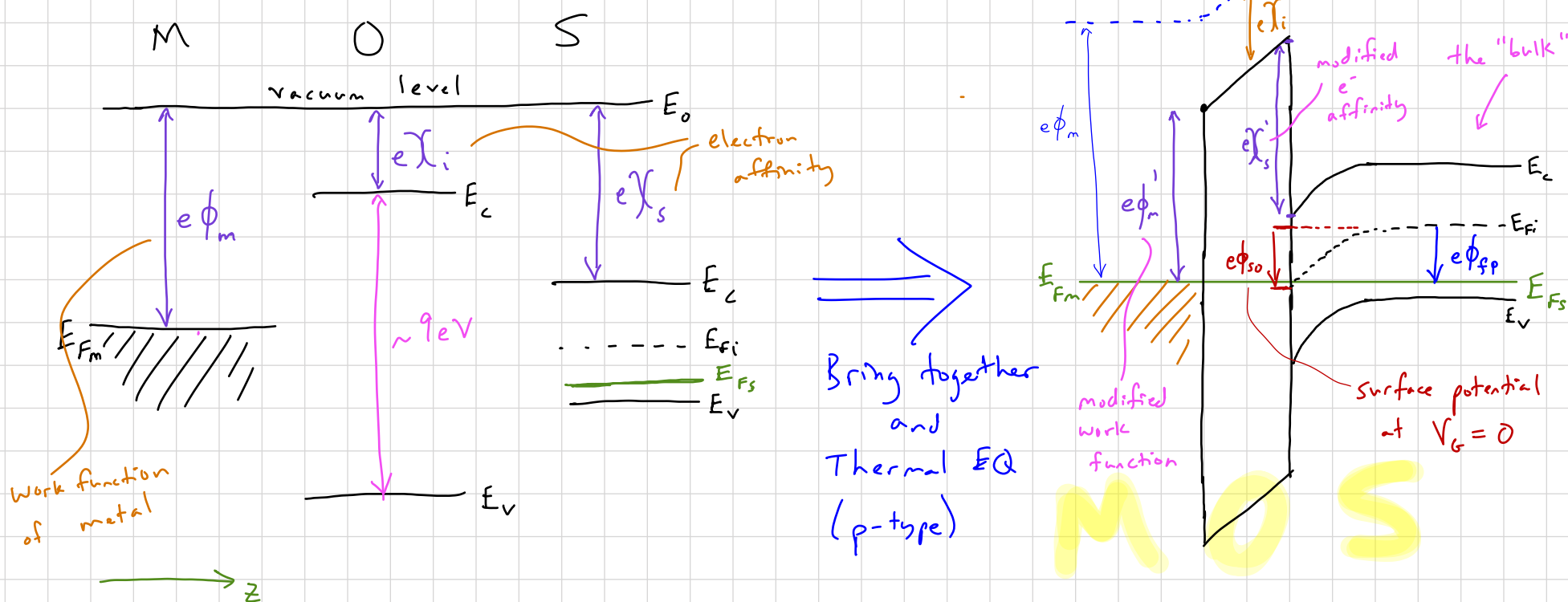


→ Metal-oxide-semiconductor (MOS) Capacitor is the core of MOS Field-Effect Transistors (MOSFETs)



MOS Energy Band Diagram at $V_G = 0$



→ For all MOS analysis, assume thermal EQ in S.C. (no current flowing in it)
 $\equiv E_{Fs}$ constant in S.C. and S.C. is grounded $\Rightarrow E_{Fs}$ does not move!!

→ Also fixed is distance between E_v, E_c and E_{Fm} in S.C.

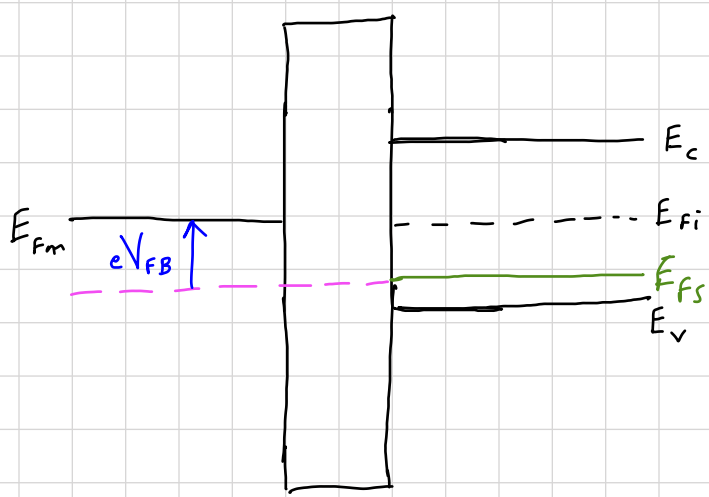
→ E_{Fm} is like a handle that "moves" under applied V_G , dragging $E_{c,v}$ with it!!

→ All band bending created in the diagram above (@ $V_G = 0$) is from difference in metal & S.C. work functions:

$$\phi_{ms} = \left[\phi'_m - \left(\chi' + \frac{E_g}{2e} + \phi_{fp} \right) \right] \quad \text{— p-type S.C.}$$

$$\phi_{ms} = \phi'_m - \left(\chi' + \frac{E_g}{2e} - \phi_{fn} \right) \quad \text{— n-type S.C.}$$

Flat-Band Voltage: voltage required to achieve no band bending in S.C. (no space charge)



$$V_{FB} = \phi_{ms} \quad (\text{when no charge in oxide})$$

Typically, there is some amount of charge trapped in the oxide (Q'_{ss}) and is physically right next to S.C. surface:

$$V_{FB} = \phi_{ms} - \frac{Q'_{ss}}{C_{ox}}$$

careful of units (C/cm^2 or cm^{-2})
mos capacitance

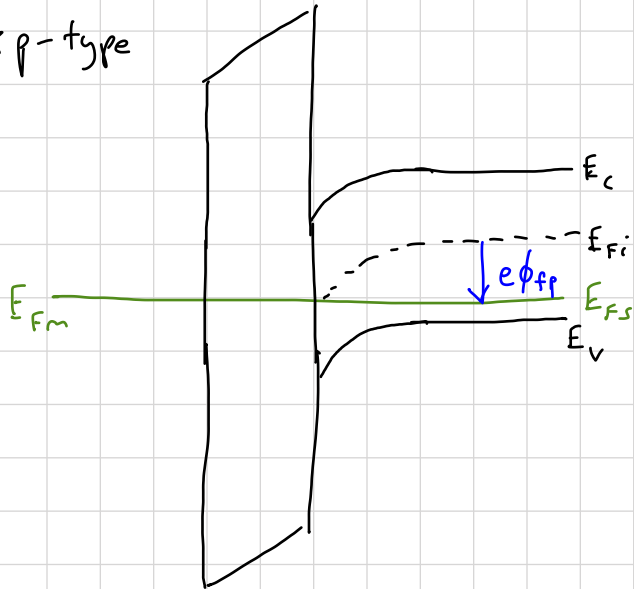
$$C_{ox} = \frac{\epsilon_{ox} \epsilon_0}{t_{ox}}$$

$Q = CV_G$

Function of MOS Capacitor

★ p-type

$$V_G = 0$$



p-type

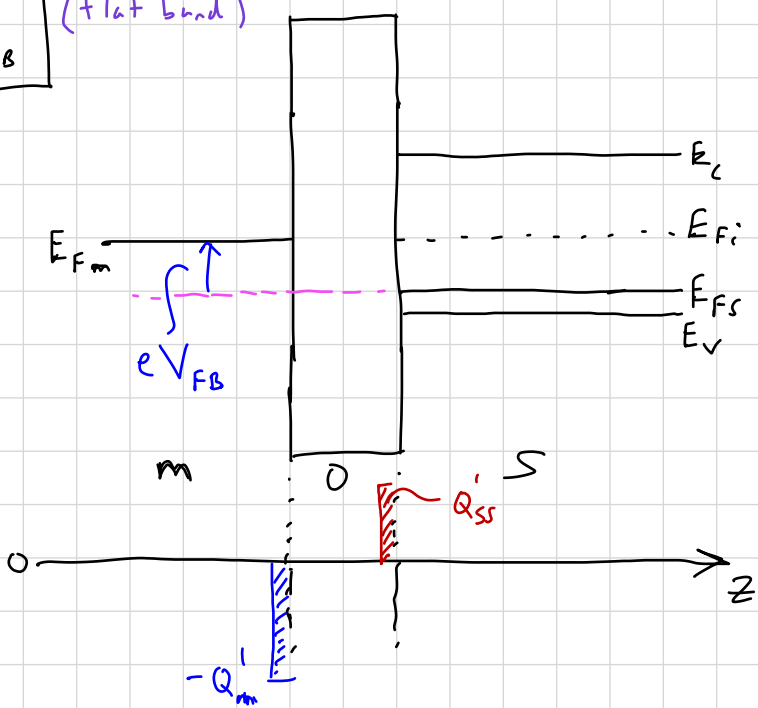
n-type

$$\phi_{fp} = V_t \ln\left(\frac{N_A}{n_i}\right)$$

$$\phi_{fn} = V_t \ln\left(\frac{N_d}{n_i}\right)$$

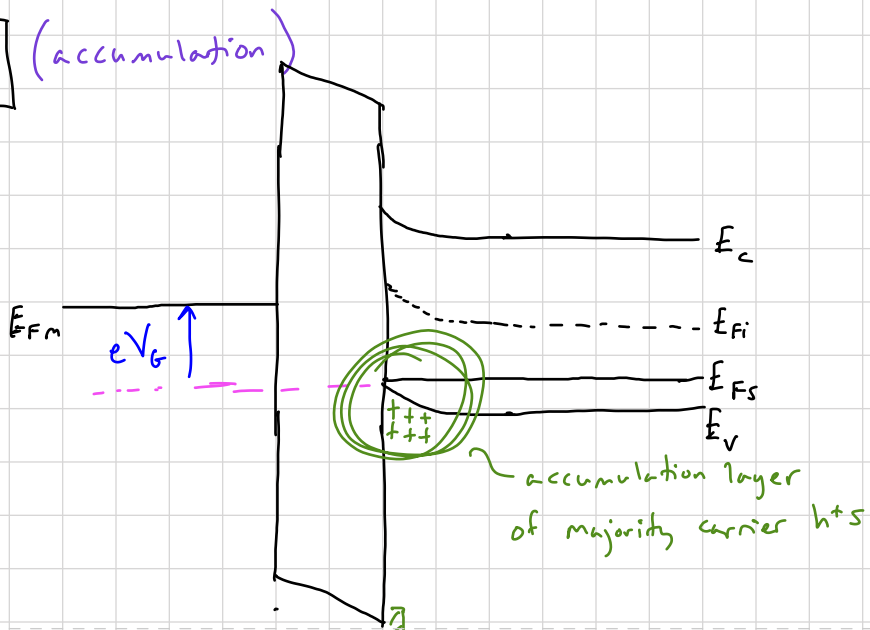
true for all bias conditions

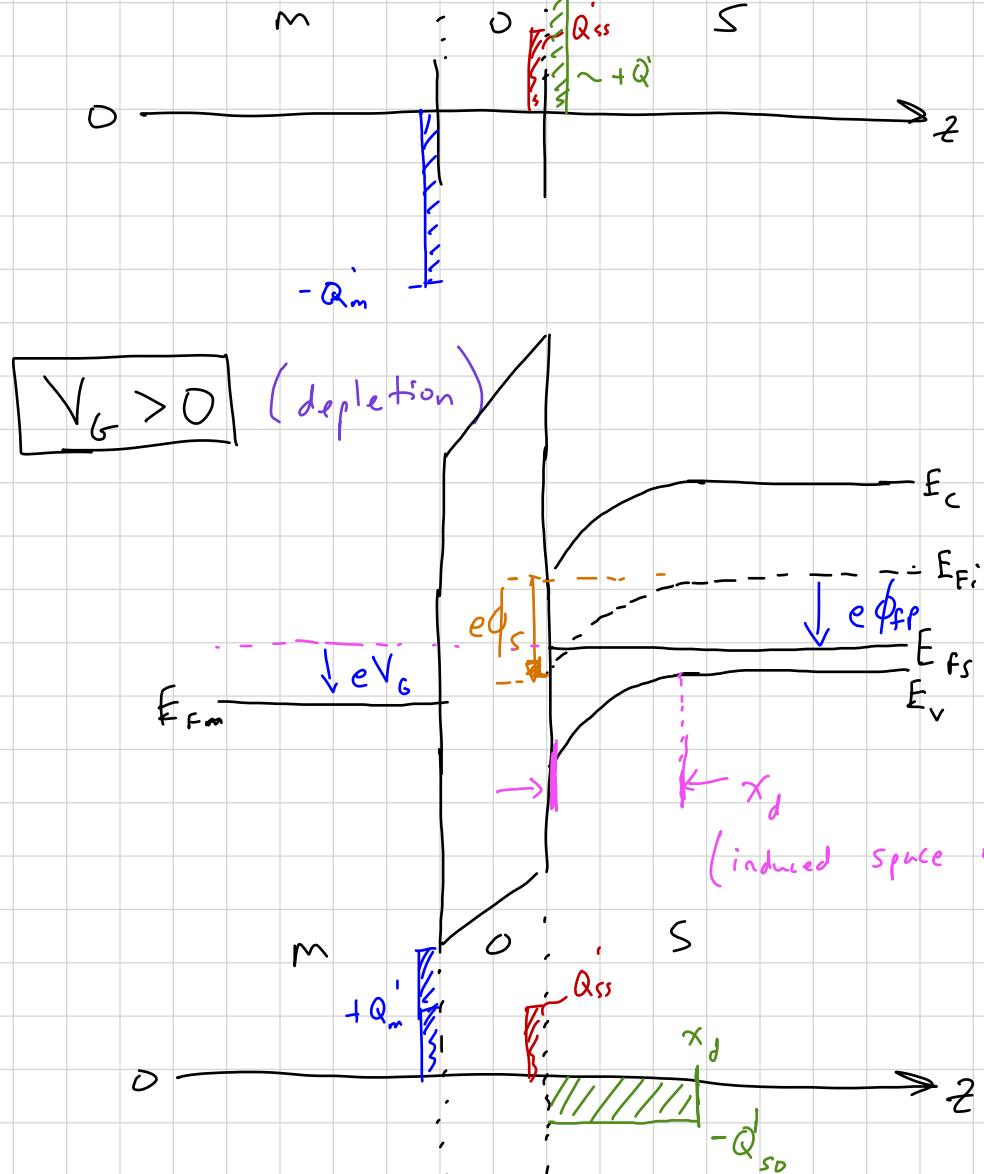
$$V_G = V_{FB} \quad (\text{flat band})$$



$$V_{FB} = \phi_{ms} - \frac{Q'_{ss}}{C_{ox}}$$

$$V_G < 0 \quad (\text{accumulation})$$

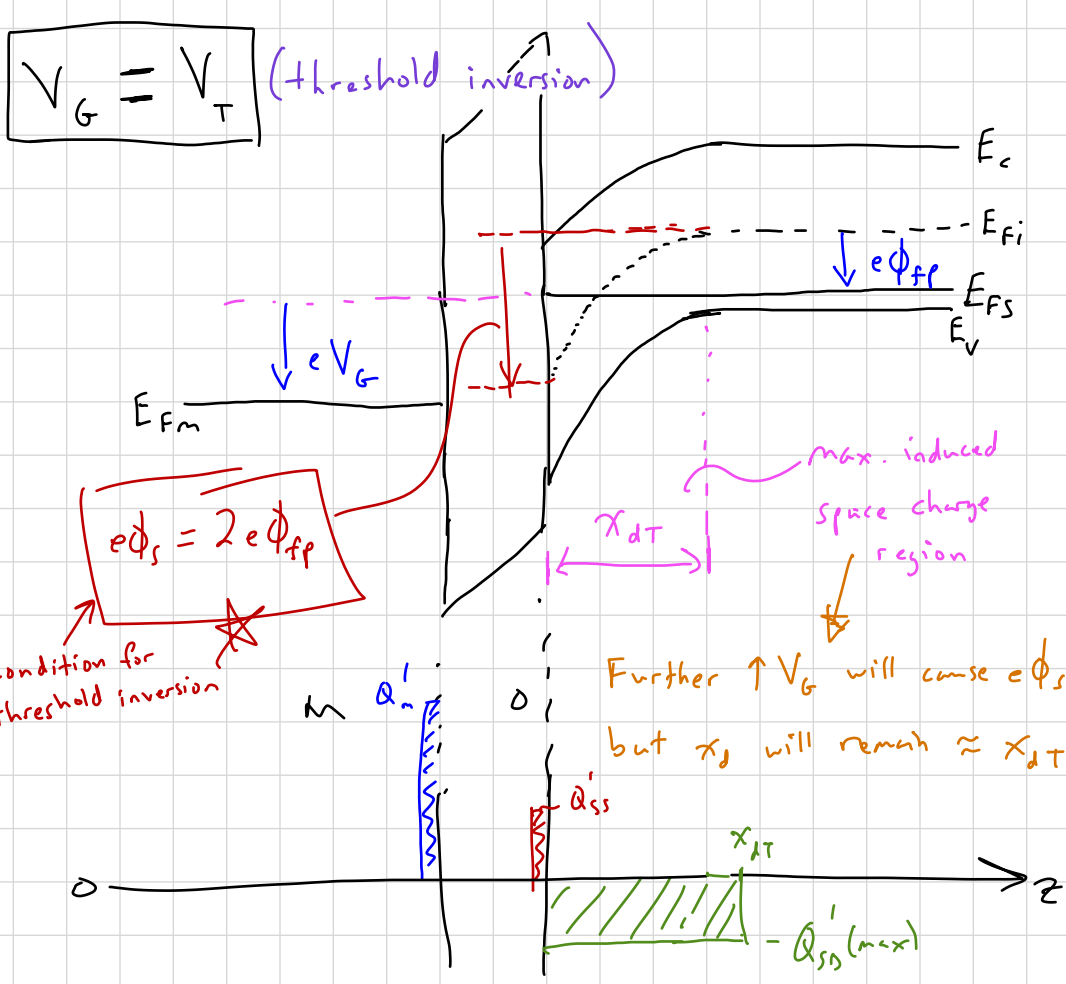




true for all bias conditions

$$x_d = \left(\frac{2\epsilon_s \epsilon_0 \phi_s}{e N_a} \right)^{1/2} \quad x_d = \left(\frac{2\epsilon_s \epsilon_0 \phi_s}{e N_d} \right)^{1/2}$$

$$e\phi_s = E_{Fi}|_{\text{bulk}} - E_{Fi}|_{\text{surface}}$$



$$x_{dT} = \left(\frac{4\epsilon_s \epsilon_0 \phi_{fp}}{e N_a} \right)^{1/2}$$

$$x_{dT} =$$

$$|Q'_{sd}(\text{max})| = e N_a x_{dT}$$

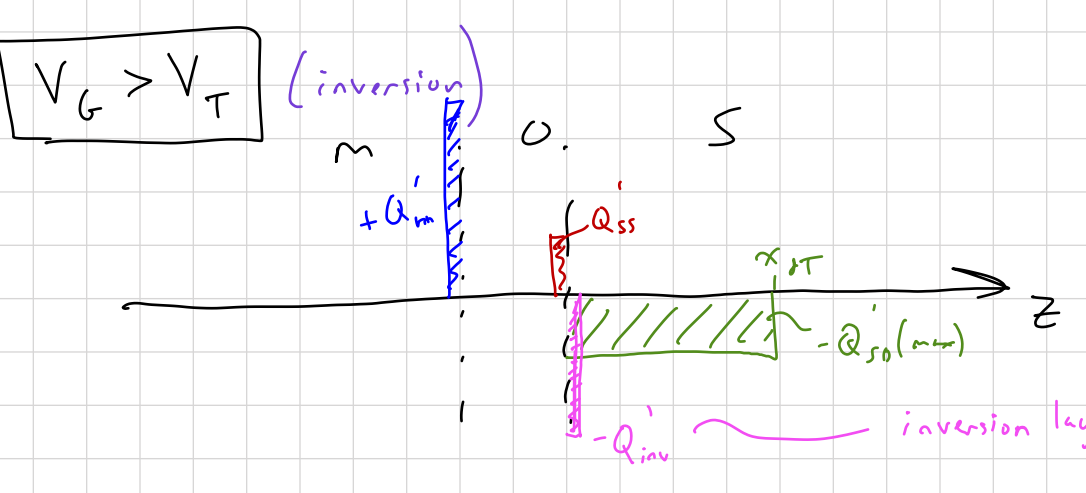
$$|Q'_{sd}(\text{max})| = e N_d x_{dT}$$

$$V_{TN} = \frac{|Q'_{sd}(\text{max})|}{C_{ox}} - \frac{Q_{ss}}{C_{ox}} + \phi_{ms} + 2\phi_{fp}$$

$$V_{TP} = \left(-|Q'_{sd}(\text{max})| - Q_{ss} \right) \frac{t_{ox}}{\epsilon_{ox} \epsilon_0} + \phi_{ms} - 2\phi_{fn}$$

Condition for threshold inversion

Further $\uparrow V_G$ will cause $e\phi_s \uparrow$ but x_d will remain $\approx x_{dT}$



inversion layer (must form to balance added Q_m charge)